

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10004646	12/03/2001	430	492.23	2AB1 4756	2AB1 KALUODA

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\*\*CONTINUING DATA VERIFIED:

\*\* FOREIGN APPLICATIONS VERIFIED:

JAPAN 2000-366847 12/01/2000

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	ATTORNEY DOCKET NO
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no			4641-61503
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no			
Verified and Acknowledged: Examiners's initials			

TITLE : Devices and methods for monitoring respective operating temperatures of components in a microlithography apparatus

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED

ISSUE FEE	
Amount Due	Date Paid

☐ TERMINAL  
DISCLAIMER

Assistant Examiner

Primary Examiner

PREPARED FOR ISSUE

CLAIMS ALLOWED

Total Claims	Print Claim for O.G.

DRAWING

Sheets Drawg.	Figs. Drawg.	Print Fig.

Application Examiner

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